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PRODUCT BULLETIN

Generic Copy

ISSUE DATE:	13-Jun-2013
NOTIFICATION:	15708
TITLE:	MMPF0100 C&I Devices Test Expansion from ASE Korea to Freescale Tianjin China Test Facility
EFFECTIVE DATE:	14-Jun-2013

DEVICE(S)

MPN
MMPF0100F0EP
MMPF0100F0EPR2
MMPF0100F1EP
MMPF0100F1EPR2
MMPF0100F2EP
MMPF0100F2EPR2
MMPF0100NPEP
MMPF0100NPEPR2

AFFECTED CHANGE CATEGORIES

- TEST SITE

DESCRIPTION OF CHANGE

Freescale Semiconductor is announcing the test site expansion for the MMPF0100 C&I devices listed in this notification, from the current ASE Korea Final Test Facility to the Freescale Tianjin, China Final Test Facility.

REASON FOR CHANGE

Qualification of the Freescale Tianjin China Final Test Facility to improve manufacturing flexibility and customer support.

ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR

RELIABILITY)

There is no impact on device form, fit, function or reliability.

NOTE:
THE CHANGE(S) SPECIFIED IN THIS NOTIFICATION WILL BE IMPLEMENTED ON THE EFFECTIVE DATE LISTED ABOVE. To request further data or inquire about the notification, please enter a Service Request

For sample inquiries - please go to www.freescale.com

QUAL DATA AVAILABILITY DATE: 31-May-2013

QUALIFICATION STATUS: COMPLETED

QUALIFICATION PLAN:

Freescale Semiconductor Manufacturing standard specification was followed for the test expansion. See the attached product qualification data.

RELIABILITY DATA SUMMARY:

See attached.

ELECTRICAL CHARACTERISTIC SUMMARY:

Parametric comparison between ASE Korea and Freescale Tianjin, China was completed. Parameters show no significant difference.

CHANGED PART IDENTIFICATION:

There is no change to the orderable part number.

ATTACHMENT(S):

External attachment(s) FOR this notification can be viewed AT:

15708_MMPF0100_Test_Location_Addition_Qual_Results.pdf